Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/801,219	MEGAW ET AL.	
Examiner	Art Unit	
Y. J. Han	2838	

SEARCHED					
Class	Subclass	Date	Examiner		
323	312				
	313				
	314				
	315				
	316				
	907				
341	119				
327	539				
326	32				
323	318				
Search	updated	7/10/2006	/JH/		
Search	updated	10/28/2006	JH		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
See search report		10/30/2006	JH		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		